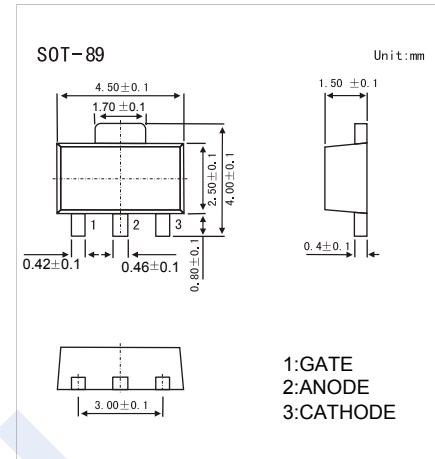


## SCR Thyristor

### BT169 (KT169)

#### ■ Features

- Repetitive peak off-state voltages :400V
- Average on-state current :0.5A
- RMS on-state current :0.8A
- Non-repetitive peak on-state current :8A



#### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Peak Repetitive Forward and Reverse Blocking Voltages	BT169-400 $V_{DRM} V_{RRM}$	400	V
Average on-state Current	$I_T(AV)$	0.5	A
Forward Current RMS	$I_T(RMS)$	0.8	
Non-Repetitive Peak on-state Current (t=10ms)	$I_{TSM}$	8	
Non-Repetitive Peak on-state Current (t=8.3ms)		9	
Circuit Fusing Considerations (t = 10ms)	$I^2t$	0.32	$A^2s$
Repetitive Rate of rise of on-state Current after Triggering	$dI_T/dt$	50	A/us
Peak Gate Current	$I_{GM}$	1	A
Peak Gate Voltage	$V_{GM}$	5	V
Peak Gate Voltage — Reverse	$V_{GRM}$	5	V
Peak Gate Power — Forward	$P_{GM}$	2	W
Average Gate Power — Forward	$P_{GF(AV)}$	0.1	
Thermal Resistance Junction to Ambient	$R_{thJA}$	150	K/W
Thermal Resistance Junction to Case	$R_{thJC}$	60	
Junction Temperature	$T_J$	125	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-40 to 150	

## SCR Thyristor

### BT169 (KT169)

■ Electrical Characteristics (Ta = 25°C, unless otherwise noted.)

Parameter	Symbol	Test Conditions	Min	Typ.	Max	Unit
Peak Repetitive Forward and Reverse Blocking Voltages	V <sub>DRM</sub> V <sub>RRM</sub>	I <sub>DRM</sub> =I <sub>RRM</sub> 50μA	400			V
Off-state Leakage Current	I <sub>D,IR</sub>	V <sub>DRM</sub> =V <sub>RRM</sub> (max); T <sub>j</sub> =125°C; R <sub>GK</sub> =1kΩ			0.1	mA
On-state Voltage	V <sub>TM</sub>	I <sub>T</sub> =1A			1.5	V
Gate Trigger Voltage	V <sub>GT</sub>	V <sub>D</sub> =12V, I <sub>T</sub> =10mA			0.8	
		V <sub>D</sub> = V <sub>DRM</sub> (max), I <sub>T</sub> =10mA; T <sub>j</sub> =125°C	0.2			
Gate Trigger Current (Continuous dc)	I <sub>GT</sub>	V <sub>D</sub> =12V, I <sub>T</sub> =10mA			200	μA
Latching Current	I <sub>L</sub>	V <sub>D</sub> =12V, I <sub>GT</sub> =0.5mA; R <sub>GK</sub> =1kΩ			6	mA
Holding Current	I <sub>H</sub>	V <sub>D</sub> =12V, I <sub>GT</sub> =0.5mA; R <sub>GK</sub> =1kΩ			5	
Critical Rate of rise of off-state Voltage	dV <sub>D</sub> /dt	V <sub>DM</sub> =67% V <sub>DRM</sub> (max); T <sub>j</sub> =125 °C exponential waveform; R <sub>GK</sub> =1kΩ		25		V/us
Gate Controlled turn-on time	t <sub>gt</sub>	I <sub>TM</sub> =2A; V <sub>D</sub> =V <sub>DRM</sub> (max), G=10mA; di <sub>G</sub> /dt=0.1A/us		2		us
Circuit Commutated turn-off time	t <sub>q</sub>	V <sub>D</sub> =67% V <sub>DRM</sub> (max); T <sub>j</sub> =125°C, T <sub>M</sub> =1.6A; V <sub>R</sub> =35V; di <sub>TM</sub> /dt=30A/us, dV <sub>D</sub> /dt=2V/us; R <sub>GK</sub> =1kΩ		100		

■ Classification of I<sub>GT</sub> (μA)

Type	BT169-400	BT169-400A	BT169-400B
Range	0-200	10-30	30-60
Marking	BT/C39	BT/C35	BT/C36

### SCR Thyristor BT169 (KT169)

■ Typical Characteristics

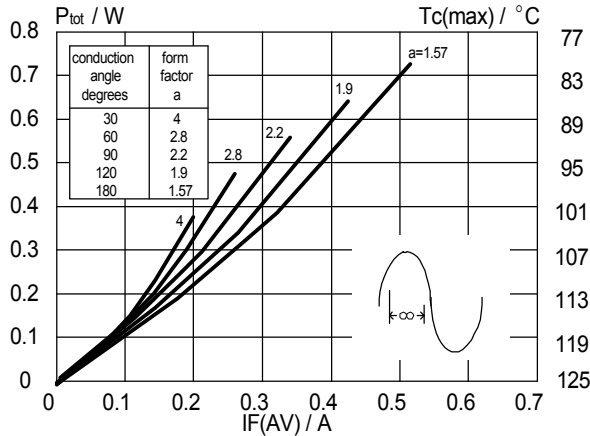


FIG.1 Maximum on-state dissipation,  $P_{tot}$ , versus average on-state current,  $I_{T(AV)}$ , where  $a = \text{form factor} = I_{T(RMS)} / I_{T(AV)}$

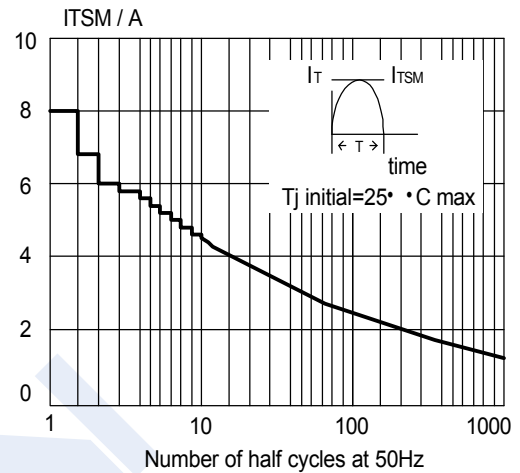


FIG.4 Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents,  $f = 50\text{Hz}$ .

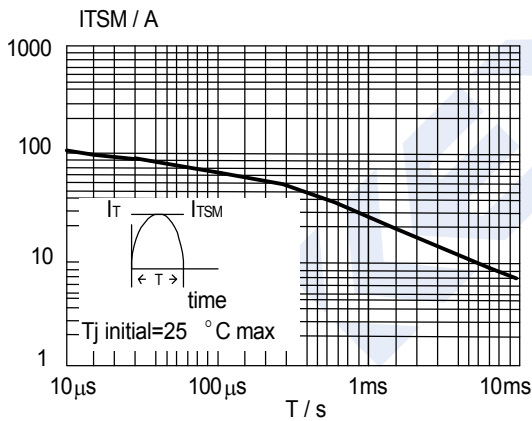


FIG.2 Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \leq 10\text{ms}$ .

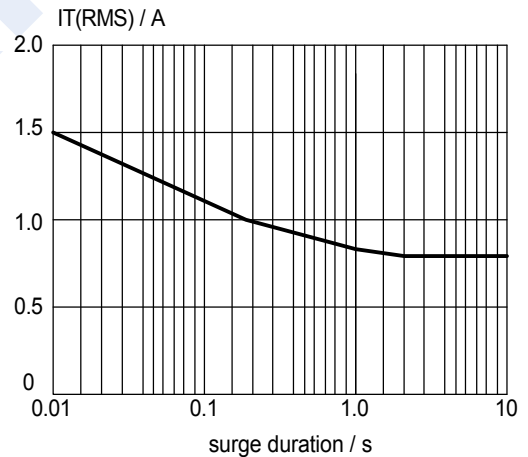


FIG.5 Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents,  $f = 50\text{Hz}$ ;  $T_{lead} \leq 83^\circ\text{C}$

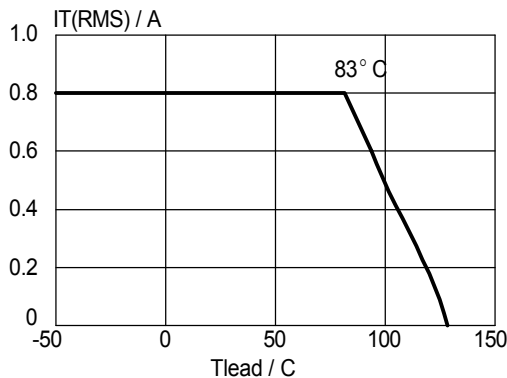


FIG.3 Maximum permissible rms current  $I_{T(RMS)}$ , versus lead temperature,  $T_{lead}$

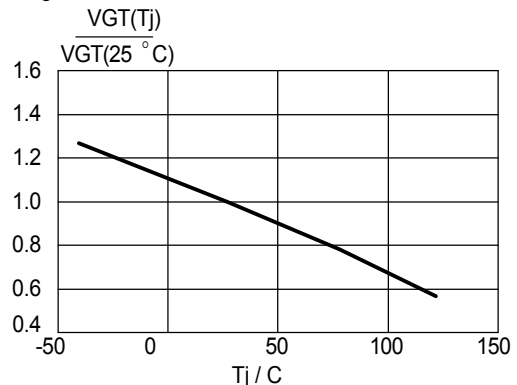


FIG.6 Normalised gate trigger voltage  $V_{GT}(T_j) / V_{GT}(25^\circ\text{C})$ , versus junction temperature  $T_j$

## SCR Thyristor BT169 (KT169)

### ■ Typical Characteristics

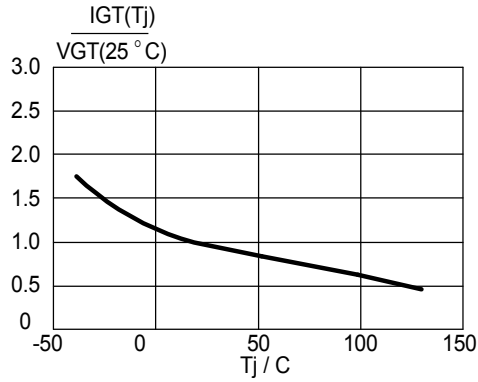


FIG.7 Normalised gate trigger current  $I_{GT}(T_j)/I_{GT}(25^\circ\text{C})$ , versus junction temperature  $T_j$

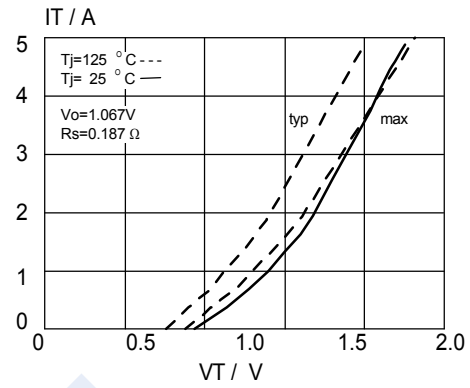


FIG.10 Typical and maximum on-state characteristic.

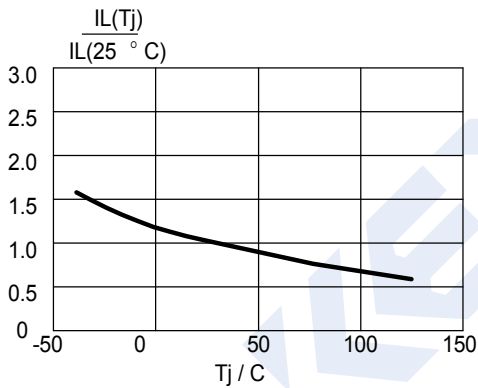


FIG.8 Normalised latching current  $I_L(T_j) / I_L(25^\circ\text{C})$ , versus junction temperature  $T_j$ ,  $R_{GK} = 1\text{K}\Omega$

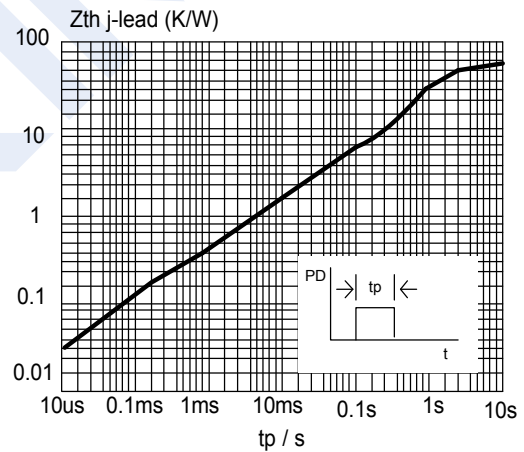


FIG.11 Transient thermal impedance  $Z_{th\ j\text{-lead}}$ , versus pulse width  $t_p$ .

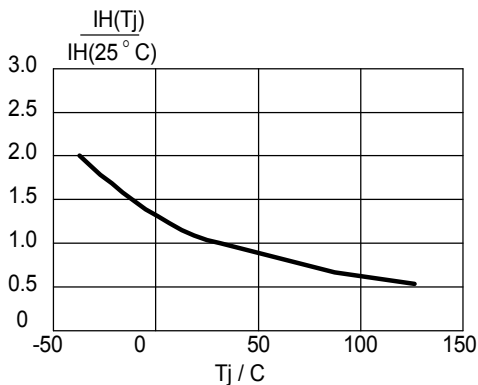


FIG.9 Normalised holding current  $I_H(T_j)/I_H(25^\circ\text{C})$ , versus junction temperature  $T_j$ ,  $R_{GK} = 1\text{K}\Omega$

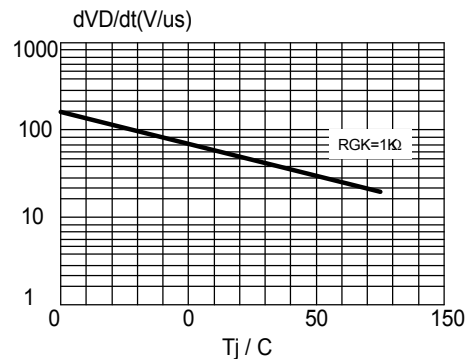


FIG.12 Typical, critical rate of rise of off-state voltage,  $dV_D/dt$  versus junction temperature  $T_j$ .